# SLOVENSKI STANDARD

# SIST EN 60512-5-2:2003

oktober 2003

Connectors for electronic equipment - Tests and measurements - Part 5-2: Currentcarrying capacity tests - Test 5b: Current-temperature derating (IEC 60512-5-2:2002)

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### EUROPEAN STANDARD

## EN 60512-5-2

## NORME EUROPÉENNE

## EUROPÄISCHE NORM

April 2002

ICS 31.220.10

English version

### Connectors for electronic equipment -Tests and measurements Part 5-2: Current-carrying capacity tests -Test 5b: Current-temperature derating (IEC 60512-5-2:2002)

Connecteurs pour équipements électroniques -Essais et mesures Partie 5-2: Essais de courant limite -Essai 5b: Taux de réduction de l'intensité en fonction de la température (CEI 60512-5-2:2002) Strombelastbarkeit (CEI 60512-5-2:2002) Strombelastbarkeit (CEI 60512-5-2:2002)

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European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

#### Central Secretariat: rue de Stassart 35, B - 1050 Brussels

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The following dates were fixed:

-	latest date by which the EN has to be implemented at national level by publication of an identical	
	national standard or by endorsement	(dop) 2003-01-01
-	latest date by which the national standards conflicting with the EN have to be withdrawn	(dow) 2005-04-01

#### **Endorsement notice**

The text of the International Standard IEC 60512-5-2:2002 was approved by CENELEC as a European Standard without any modification.

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# NORME INTERNATIONALE INTERNATIONAL STANDARD

CEI **IEC** 60512-5-2

Première édition First edition 2002-02

Connecteurs pour équipements électroniques – Essais et mesures –

Partie 5-2: Essais de courant limite – Essai 5b: Taux de réduction de l'intensité en fonction de la température (standards.iten.al)

Connectors for electronic equipment – https://stadads.ich.averagestore.com/ Tests\_and\_measurements\_-

Part 5-2: Current-carrying capacity tests – Test 5b: Current-temperature derating

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Commission Electrotechnique Internationale International Electrotechnical Commission Международная Электротехническая Комиссия



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#### INTERNATIONAL ELECTROTECHNICAL COMMISSION

#### CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

#### Part 5-2: Current-carrying capacity tests – Test 5b: Current-temperature derating

#### FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of the IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested National Committees.
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- 5) The IEC provides not marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with one of its standards5-2-2003
- 6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60512-5-2 has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

This standard cancels and replaces test 5b of IEC 60512-3, issued in 1976, and constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/1137/FDIS	48B/1188/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication will remain unchanged until 2007. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

#### CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

#### Part 5-2: Current-carrying capacity tests – Test 5b: Current-temperature derating

#### 1 Scope and object

This part of IEC 60512, when required by the detail specification, is used for testing electromechanical components within the scope of IEC technical committee 48. This test may also be used for similar devices when specified in a detail specification.

The object of this test is to detail a standard test method to assess the current-carrying capacity of electromechanical components at elevated ambient temperature.

#### 2 General conditions

#### 2.1 Determining the current-carrying capacity curve

The current-carrying capacity is limited by the thermal properties of the materials which are used for the contacts, terminals as well as the insulating materials of housing. Therefore, it is a function of the self-generated heat and the ambient temperature at which a device operates.

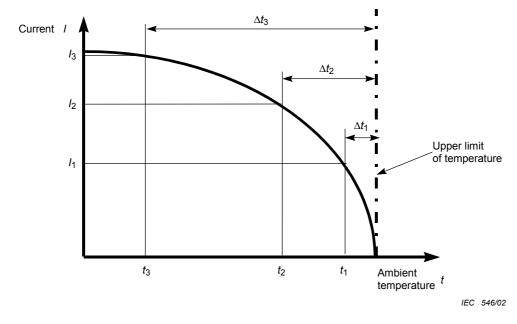
#### SIST EN 60512-5-2:2003

Using the measuring, conditions, given  $g_{1,2}$ , the  $g_{1,2}$ , the  $g_{1,2}$  and  $g_{2,2}$ , the  $g_{1,2}$  and  $g_{2,2}$ , the  $g_{1,2}$  and  $g_{2,2}$  and

#### $t_{\rm b} - t_{\rm u} = \Delta t$ (K)

The relation between the current, the temperature rise and the ambient temperature of the component is represented by a curve as shown in figure 1. Unless otherwise specified in the detail specification, the temperature rise is based upon the mean current of three specimens. The mean value derived from the measured values of these three specimens serves as the basic curve. At least three points of the basic curve shall be established.

The permissible upper-limit temperature of the materials employed is plotted as a vertical line on the graphs shown in figures 1 and 2, with current *I* as the ordinate and temperature *t* as the abscissa. The temperature rise  $\Delta t$  (mean value of three specimens), determined at current  $I_n$ , is deducted. From this, the maximum permissible ambient temperature  $t_u$  for the load current  $I_n$  is obtained, since the sum of the ambient temperature  $t_u$  and the temperature rise  $\Delta t$  shall not exceed the upper temperature limit of the materials.



NOTE An upper temperature limit, which may be imposed by e.g. material considerations, may truncate the curve. Figure 1 – Construction of the basic current-carrying curve

#### 2.2 Derating curve

#### SIST EN 60512-5-2:2003

A derating curve, see/figured2rcderived from the basic curved see figure 1, determined in accordance with 2.1, shall be specified in the relevant detail specification. This curve takes into account variations in specimens as well as errors in temperature measurements in the measuring equipment.

The derating factor is justified because the current-carrying capacity may be further limited by external factors, for example the size of the wire and unequal distribution of the loaded circuits. If these factors result in a current-carrying capacity other than that which may be expected due to thermal limitations, then a revised value shall apply.

#### 2.3 Application of the current-carrying capacity curve

The derating curve determined in accordance with 2.2 represents the official current-carrying capacity curve as defined by this standard. Since it gives the maximum permissible current as a function of the ambient temperature, it is truly a derating curve. The cross-hatched area shown in figure 2 indicates the permissible operating range.

This derating curve is obtained by applying a reduction factor of 0,8 on the current value of the basic current-carrying curve, unless otherwise clearly specified on the derating curve.

NOTE If the detail specification specifies current-carrying capacity data, then the current-carrying capacity curve given in this standard must be cited. If values in tabular form are preferred, they should coincide with the current-carrying capacity curve.

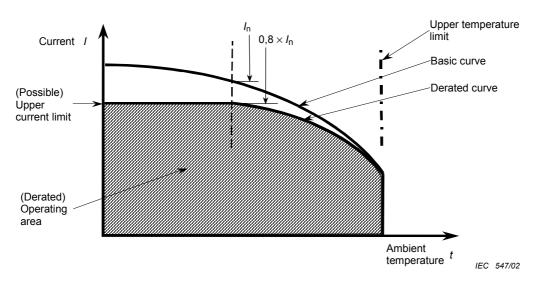


Figure 2 – Derating curve derived from the basic curve

#### 3 Conditions of the test iTeh STANDARD PREVIEW

#### 3.1 Test set-up

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**Enclosure** – The measurement shall be carried out in air as undisturbed as possible. Therefore, the specimen shall be mounted in an enclosure which protects the immediate environment from external movements of air. The enclosure should be made of a non-heatreflective material. 117c917b025b/sist-en-60512-5-2-2003

The sides of the enclosure may be movable to accommodate different specimen sizes. The sides shall not be closer than 200 mm from the edges of the specimen. The enclosure may have a lid, any such lid shall be provided with ventilation apertures to minimize any rise in ambient temperature caused by the heating effect of the specimen under test.

**Mounting** – The specimen is to be arranged in the enclosure in a horizontal plane, 50 mm above the bottom of the enclosure and at least 150 mm below the top and equidistant from the sides. As far as possible, the specimen shall be in free suspension. If this is not possible, a thermal insulating material with a thermal conductivity  $\leq 2$  W/mK may be used, provided that not more than 20 % of the surface of the specimen is in contact with the insulating material.

**Wiring –** The specimen shall be connected with wires of suitable cross-section for the maximum current to be expected or according to the size of the termination. In order to reduce external heat dissipation to a minimum, at least the length of the connecting wires given in table 1 shall be within the measuring enclosure. In the case of multipole specimens, all contacts shall be wired in series with wire the same size as the connecting wires. These links shall be at least twice the minimum length specified in table 1.

The manufacturer's recommended, or industry standards, wiring method and tooling shall be used, unless otherwise stated in the detail specification.

NOTE  $\,$  In the case of specimens with moving contacts, care must be taken that the contacts are not disturbed by the connecting wires.

A mated connector set is considered to be a single specimen.